Form PTO 1449 (Modified)		U.S. DEPARTMENT OF PATENT AND TRADEM		ATTY DOCKET NO. 214056US0CONT		SERIAL N	09/960,487	
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FOREIGN PATENT DOCUMENTS								
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1	AO	51-72937	06-24-76	Japan w/English Abstract			X	
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~X	AR	09-122974A	05-199	Japan (English Translation Only)		×		
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
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*Examiner:	*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							
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